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**IDENTIFYING UNKNOWN MINERALS AND COMPOUNDS FROM
X-RAY DIFFRACTION PATTERNS USING THE JOHNSON AND
VAND FORTRAN IV COMPUTER PROGRAM**

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and

**Ames Research Center
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<p>The contents of this document are designed to serve two purposes. First, to provide automated computer identification of minerals and compounds from unknown samples for those staff members (mineralogists and geochemists) in the Planetary Science and Applications Branch, Ames Research Center, who have been using the more traditional manual identification technique employing the Fink index. Second, to provide detailed instructions and worked examples for use in graduate level courses in mineralogy (Geol 211) and X-ray analysis applications (Geol 255) at San Jose State University. This document presumes the reader has either had prior course work or direct experience in mineral and rock type identification employing X-ray diffraction and emission techniques.</p> <p>Appendix I, a compendium of computer printouts describing worked examples discussed in Section IV of this report, is available from either Dr. Marshall Maddock (San Jose State University, Department of Geology) or Maxwell Blanchard (Ames Research Center, Planetary Science and Applications Branch).</p>			
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PREFACE

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IDENTIFYING UNKNOWN MINERALS AND COMPOUNDS FROM X-RAY

DIFFRACTION PATTERNS USING THE JOHNSON AND

VAND FORTRAN IV COMPUTER PROGRAM

Frank T. Kyte* and Maxwell B. Blanchard

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I. INTRODUCTION

The Johnson and Vand FORTRAN IV Program for Identification of Multiphase Powder Diffraction Data can be a useful tool to interpret complex diffraction patterns from mixtures of minerals. The program compares d-spacings and intensities of unknown diffraction patterns with every compound in the ASTM X-ray diffraction file. It then prints out every compound that satisfies the input parameters and data. These parameters include: chemical information, intensity match requirements, allowable error in pattern measurement, number and 2θ range of d-spacings observed, and background intensity. The 10 standards having the best match are then subtracted from the original unknown pattern, leaving a residual pattern.

This report describes the program operation and how to interpret the output. Input parameters are discussed in enough detail that a new user can understand why patterns are accepted or rejected by the computer. A principal reference for this report is "FORTRAN IV Program (Version 10) for the Identification of Multiphase Unknown Powder Diffraction Patterns" by G. G. Johnson, Jr. and V. Vand, published and distributed by ASTM, 1969.

II. JOHNSON - VAND PROGRAM DESCRIPTION

A. Input Parameters

Successful use of this program depends on the choice of input parameters. The most important of these are the error window and the log intensity match, which define how closely a standard pattern must match the unknown in its d-spacings and intensities. The parameters log intensity match, number, and percent of line matches apply only to the range of d-spacings within the input high and low range of 2θ . These five parameters interact in a very complicated way. When the d-spacing range is unusually narrow, number and percent should probably be decreased and log intensity match increased.

(1) *Subfile option*- The subfiles are alloys, organics, inorganics, minerals, and dual (inorganic compounds). The subfile option allows the operator to limit the search, and thus the output, to subfiles in which he is interested.

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(2) *Resolution*- This parameter instructs the program that a high-resolution Guinier camera has been used and the intensities are "fuzzed" to give a "normal" resolution. This parameter is not used for Debye-Scherrer diffraction patterns or for diffractometer scans.

(3) *Error window*- The error window is defined by a variable d^* which, unlike $d(\text{\AA})$, has a linear relationship with θ and best approximates a constant error window for the observed range of θ values. The error window is a very important parameter because it defines how closely a standard line must match a d-spacing in the unknown pattern.

Errors in the diffracted line measurement (in Angstroms) are roughly proportional to d^2 . A constant error window is best approximated by transformation to reciprocal spacings that are $1/d$. When used by the program, the reciprocal spacings are multiplied by 1000, rounded down to the nearest integer, and added to 0.5. Thus, input d-spacings from 200 \AA to 0.6 \AA are represented by a set of numbers from 5.5 to 1666.5 (e.g., 5.5, 6.5, 7.5, . . . , 1666.5). This new number, d^* , allows the program to perform integer arithmetic for much faster calculations and defines a constant error window for any value of θ .

$$d^* \cong 1/d(\text{\AA}) \times 1000$$

Figure 1 shows a plot of $d(\text{\AA})$ and d^* versus θ for $\text{CuK}\alpha = 1.5418$.

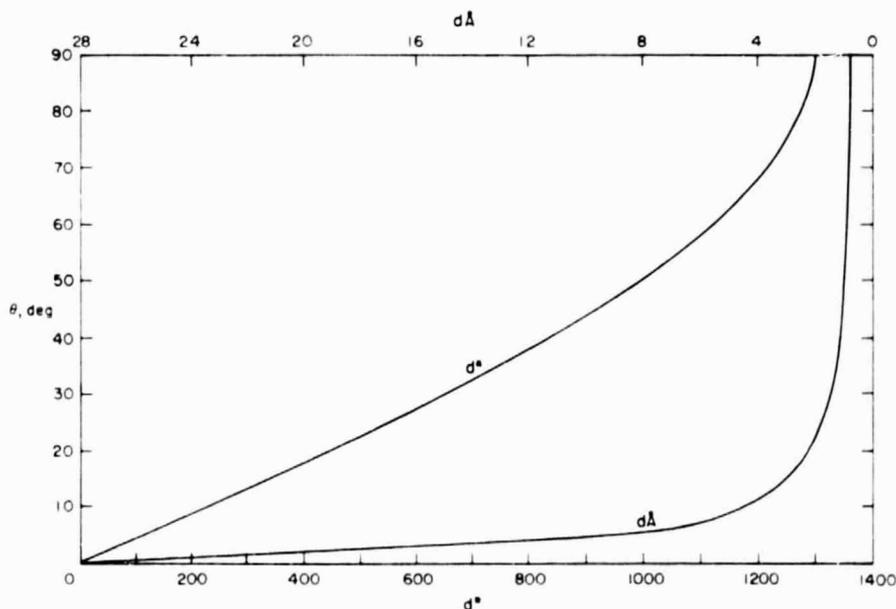


Figure 1.- Plot of d^* and $d(\text{\AA})$ versus θ for $\text{CuK}\alpha = 1.5418$. (To convert from $d(\text{\AA})$ to d^* read d in \AA from upper scale using line labeled $d(\text{\AA})$ which corresponds to a θ value on left hand scale. Using this θ value read the corresponding d^* using the line labeled d^* whose value is given on the lower scale. For example, a d -value of 2.98 \AA corresponds to an angle of 15 $^\circ$ θ and is equivalent to 335 d^* .)

To determine the optimum error window for the instruments at Ames Research Center, a mixture of approximately equal weights of flourite, galena, rutile, chromite, and olivine was X-rayed using the diffractometer and the Debye-Scherrer camera.

To see how much error could be expected, d^* was calculated for multiple measurements on the Debye-Scherrer powder films and for each of the diffractometer scans shown in Tables 1 and 2, respectively. The diffractometer scans were corrected because the goniometer was consistently about $0.05^\circ \theta$ too high. For 99 percent (508 measurements) of the line measurements, the maximum variation was $4d^*$, or an error of $\pm 2d^*$. Of the remaining 1 percent (5 measurements) of line measurements, the maximum variation was $6d^*$.

A nominal error window of ± 2 would seem to be appropriate for most identifications. However, inaccuracies in the ASTM file itself, or variations in d-spacings caused by solid solution, may necessitate the use of a larger window (± 3 or greater). One should be cautious of using too large an error window because it can produce a large number of possibilities, and, in some cases, the windows could even overlap, creating a continuous coverage of several degrees 2θ . Usually, a broad error window of ± 4 is suitable only for data in conjunction with chemical information.

TABLE 1.- DEBEYE-SCHERRER CAMERA FILMS

Sample pattern	Camera radius	Sample grain size	Quality of lines	Times measured	Total lines	Date
ASTM 1	114.6 mm	coarse	spotty	4	120	7/22/75
ASTM 2	114.6 mm	fine	continuous	4	112	7/24/75
ASTM 2A	57.3 mm	fine	continuous	4	66	7/28/75
ASTM 3	57.3 mm	coarse	spotty	4	95	7/29/75
ASTM 5	57.3 mm	fine	continuous	1	---	8/19/75

TABLE 2.- DIFFRACTOMETER SCANS

Sample pattern	$^\circ 2\theta/\text{min}$	cps	Slits	Peaks	Date
ASTM 4A	1	250	1/2	14	7/30/75
ASTM B	1	100	1/2	18	8/4/75
ASTM C	1	250	1	22	8/4/75
ASTM D	1/2	250	1	22	8/4/75
ASTM E	1/2	250	1/2	13	8/5/75
ASTM F	1/4	100	1/2	31	8/5/75
BSTM 1	1/4	250	1	---	10/3/75
BSTM 2	1	250	1	---	10/9/75

(4) *Log intensity match*- This very important parameter is a requirement for intensity agreement between the unknown and an ASTM standard. All intensities are input on a 3-digit scale of 1 to 100, but all program calculations are on a 1-digit log scale of 0 to 9. The 3-digit (I_3) intensities are converted to the 1-digit (I_1) log scale by the formula

$$I_1 = 5 \log I_3$$

The conversion scale thus becomes

I_3	0-1	2	3	4-6	7-10	11-15	16-25	26-39	40-63	64-100
I_1	0	1	2	3	4	5	6	7	8	9

Thus, an input intensity of 40 is equivalent to an input of 63 and very different from an input of 39. Program users should keep this in mind when inputting intensities.

Log intensity match is defined as

$$\log \text{ intensity match } (I_1) = 9 - (I_{1\text{STD}} - I_{2\text{UNK}})_{\text{MAX}}$$

where $(I_{1\text{STD}} - I_{2\text{UNK}})_{\text{MAX}}$ is the maximum intensity disagreement between any line in the standard and its counterpart in the unknown pattern. When selecting an input value for log intensity match, the user must remember that any standard pattern with a match of this value or less will be rejected as a possibility.

For example, when log intensity match is input with a value of 2(I_3) it is converted to a log scale value of 1(I_1), and then intensities of every line in the standard are compared with corresponding intensities of lines in the unknown (which may be zero if no line is present in the unknown to compare

with one in the standard pattern), and log intensity match is calculated for each line in the standard. If the log intensity match of any single line in the pattern has a value of $1(I_1)$ or lower, then the standard will be rejected as a possibility. Therefore, in this example, it is necessary that

$$9 - (I_{1\text{STD}} - I_{1\text{UNK}})_{\text{MAX}} > 1$$

or that

$$(I_{1\text{STD}} - I_{1\text{UNK}})_{\text{MAX}} \neq 8 \text{ or } 9$$

Essentially what this means, in returning to the I_3 scale, is that lines with intensities of 40 to 100 in the standard must match with corresponding lines in the unknown. Failure to do so results in rejection, even if every other line in the standard pattern except one, say with an intensity of 40, matches perfectly.

(5) *Number*- This is the minimum number of line matches that the program requires for an identification. If this minimum is set too high, a pattern may not be identified (e.g., diamond has only 5 lines).

(6) *Percent of line matches*- This parameter allows the operator to select the minimum percent of line matches between an unknown and a standard. In most cases, 33 percent should be sufficient, requiring that at least 1/3 of the lines in the standard must match the unknown pattern.

(7) *Icycle*- This parameter instructs the program to go through a second cycle, during which time, all previous parameters are increased. The amount of increase is specified by another set of parameters described in Section III. In general, it is suggested that this parameter *not* be used because *all* parameters must be increased. If *Icycle* were used to increase the error window, a larger number of standard lines could be compared, but rejection of previous matches could occur from stricter requirements for log intensity match or number.

(8) *Observed range of d-spacings*- This is defined by two parameters, DHI and DLO, which are the range of d-spacings capable of being observed in the diffraction experiment. DHI must be higher than the highest input d-spacing. For example, a 3\AA line might be the largest observed spacing when the experimental range was up to 20\AA . If DHI were input as 3\AA rather than 20\AA , then standards with strong lines between 3 and 20\AA could be matched when they should have been rejected. DLO should equal the lowest d-spacing in the unknown pattern. Note that back reflections (from Debye-Scherrer camera patterns) are often omitted in the ASTM file. It is desirable to include all of the unknown patterns down to about 1.1\AA .

(9) *Background intensity*- This parameter instructs the program to disregard all lines in the standard pattern of this value or smaller. This is

difficult to quantify on powder films and should be given as about half the lowest intensity observed. On diffractometer scans, it is a good idea to set the counter scale so that the most intense peak(s) is at about 100 on the chart. Then the background (as well as other peaks) can be read directly off the chart.

(10) *Option*- This parameter uses chemistry. If the input is MAJOR, all the compounds (regardless of chemistry) will be printed. If the input is CHEM or SOLID, then only compounds which are chemically correct will be printed in the output as potential identifications. If the input is MINOR: (a) all compounds fitting parameters for a match will be printed, and (b) if a compound is chemically correct, the intensity agreement will not be applied.

(11) *Chemical information*- Chemical information can be used in this program. It is possible to list all elements and functional groups which are known to be present and those which are known to be absent. Chemical information is highly desirable because it may narrow down a list of over 100 possibilities to less than 10 or 20. It is strongly suggested that chemistry be used whenever possible.

(12) *Preconceived possibilities*- This option is to be used for phases which are *definitely* known to be present. It can be very useful in that part of the output (described below) where standard phases are subtracted from the unknown pattern. Preconceived possibilities are always subtracted first. Thus, if a match was selected on the basis of certain lines in the unknown pattern generated by the preconceived possibility, when it is subtracted from the residual unknown pattern, it will have fewer lines to compare with and it will be scaled down to have a minimal effect on the residual pattern. This will be discussed in more detail in the next section.

B. Program Output

The program output comprises of five sections: INPUT, OUTPUT, REPORT, MATCHD, and SUBSTI. Figures 2 through 8 show a portion of the output obtained by Johnson and Vand as their own example. It was generated by a known mixture of equal weights of CaF_2 , SiO_2 , ZnS , CaCO_3 , and PbS . The pattern was obtained from a Norelco diffractometer at $1^\circ/\text{min}$, using Cu radiation and peak intensities.

(1) *INPUT*- This is a summary and description of the input parameters and data (fig. 2), and should always be checked carefully for correctness. If this section is not checked, the user might miss an error comment such as, "YOU MAY HAVE KEYPUNCHED INPUT DATA WRONG - A SPACING IS OUT OF ORDER - PROGRAM ORDERS AND WILL CONTINUE."

(2) *OUTPUT*- The OUTPUT section (fig. 3) lists every compound, regardless of chemical information (unless CHEM or SOLID options are used), that fits the input data and parameters. It also lists the various numerical measures of degree of fit of the unknown to the standard patterns, as well as a reliability factor which is a composite index calculated from the percentage of line

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***** INPUT *****

***** COMMENT** THE FOLLOWING OUTPUT WAS OBTAINED USING THE JOHNSON-VAND X-RAY POWDER DIFFRACTION SEARCH AND MATCH SYSTEM VERSION 10

***** COMMENT** PATTERNS IDENTIFIED WITH A LOG INT MATCH OF 2 OR LESS OF STANDARD IN RANGE CONSIDERED WILL NOT BE PRINTED

***** COMMENT** PATTERNS WITH LESS THAN 3 LINE MATCHES OF STANDARD ABOVE BACKGROUND IN RANGE CONSIDERED ARE NOT PRINTED

***** COMMENT** PATTERNS WITH LESS THAN 23 PERCENT MATCH OF STANDARD ABOVE BACKGROUND IN RANGE CONSIDERED ARE NOT PRINTED

***** COMMENT** BACKGROUND RATIO IS 2 (THRESHOLD MEASUREMENT VALUE)

***** COMMENT** ONLY D-SPACINGS LESS THAN 22.000 ARE USED IN THIS PHASE

***** COMMENT** ONLY D-SPACINGS GREATER THAN 1.450 ARE USED IN THIS PHASE

***** COMMENT** VALUES ABOVE ARE EXPERIMENTAL RANGE

***** COMMENT** EXPERIMENTAL RANGE IS ALWAYS GREATER THAN MEASURED D RANGE

***** COMMENT** THE FOLLOWING ELEMENTS ARE KNOWN TO BE PRESENT CA SI F U ZN S U PH

***** COMMENT** THE FOLLOWING ELEMENTS ARE KNOWN TO BE ABSENT H HE LI BE B N NE NA MG AL P CL AR K SC TI V CR MN FE CU NI CO GA GE
AS SE BR KR RB SR Y ZR NB MC TC RU RH PD AG CD IN SN SB TE I XE CS BA LA
CE PR NG PM SM EU Gd TB GY HO ER TM Yb LU HF TA W RE OS IR PT AU HG TL BI
PO AT MN FR RA AC TH PA U NP PU AM CM BK CF ES FM

***** COMMENT** THE FOLLOWING FUNCTIONAL GROUPS ARE KNOWN TO BE ABSENT S O2 P O

***** COMMENT** MAJOR COMPONENT OPTION BEING USED

***** COMMENT** WINDOW FOR THIS RUN IS 0 LF - 2

SAMPLE SAMPLE NUMBER 5 CAP2 SIZE ZNS CALCS RES UNIQUE ID# 37 01/20/72

UNKNOWN SPACINGS	AND INTENSITIES WITH ERROR WINDOW			
4.2700	14	4.3011	4.2203	
3.8600	6	3.8835	3.8241	
3.4300	01	3.4542	3.4072	
3.3500	77	3.3727	3.3276	
3.3200	26	3.3385	3.2949	
3.1700	28	3.1850	3.1299	
3.1340	34	3.1450	3.1109	

Figure 2.- INPUT. (This section should be checked carefully for correctness and for any possible error messages.)

3.0590	100	3.0534	3.0100
2.5720	77	2.5095	2.9592
2.9210	22	2.5455	2.9112
2.9990	5	2.5094	2.9095
2.4600	5	2.9722	2.9980
2.2870	12	2.2502	2.2753
2.2390	3	2.2447	2.2267
2.1300	2	2.1350	2.1209
2.1010	69	2.1115	2.0942
1.9410	3	1.9242	1.9301
1.9320	21	1.9355	1.9249
1.9161	32	1.9212	1.9000
1.8777	11	1.8850	1.8709
1.8203	5	1.8205	1.8132
1.7515	25	1.7569	1.7861
1.7674	5	1.7746	1.7621
1.7151	13	1.7197	1.7079
1.6738	4	1.6793	1.6681
1.6524	2	1.6570	1.6461
1.6320	23	1.6280	1.6273
1.5415	2	1.5468	1.5373
1.4860	5	1.4514	1.4820

Figure 2.- Concluded.

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***** CLTFLT *****

*** THE FOLLOWING PATTERNS ARE POSSIBILITIES WHICH ARE SUBSETS OF THE UNKNOWN PATTERN OF C AND I

*** NO CHEMICAL INFORMATION IS USED TO LIMIT THE FOLLOWING TABLE OF RESULTS

*** THE STAR ON THE RELIABILITY FACTOR DENOTES AGREEMENT WITH CHEMICAL INFORMATION AND THE ENTIRE PATTERN WILL APPEAR IN THE REPORT

*** THE QUESTION MARK ON THE RELIABILITY FACTOR DENOTES DIFFICULTY WITH THE CHEMICAL FORMULA

NUMBER OF LINE MATCHES	PERCENT OF STANDARD LINE MATCHES	PIPIPL INTENSITY OF LINES COMPARED	LCC INT MATCH	ZSTM NUMBER	DATA MARK	FORMULA	ALLOY PHASE DES.	RELIABILITY FACTOR
3	55	10	10	10668		K N O2		22
5	38	25	3	10778		ZN (AS C2)2		7
11	39	25	3	10782		AG2 CM U4		2
7	33	25	3	10829		CA (S C N 12) J F2 O		18
4	39	6	15	10873		SR CE U3		3
8	38	25	3	10875		ZN (P O3)2		10
8	38	15	6	10854		K2 H P G4		18
3	42	15	6	10928		NA N3		9
5	41	15	6	20580		BI4 TE S3		10
7	43	25	3	30450		K3 FE (S C4)3		18
6	42	25	3	30545		PB5 (AS U4)3 U H		11
8	35	25	3	30659		BA C O4		13
7	53	15	6	40497	*	GE U2		26
3	75	6	0	40587	*	K CL		18
3	59	25	3	40593	*	GE C2		30
4	66	25	3	40641	*	MG CE O3		12
3	100	0	15	40864	*	CA F2		42*
9	64	15	6	50428	*	S C2		34
9	75	3	25	50490	*	SI O2		43*
8	75	10	10	50492	*	ZN S		29*
3	100	0	15	50565	*	SI		13*
3	75	0	15	50566	*	ZN S		35*
6	54	15	6	50582	*	MG2 P2 G7		18
8	57	6	15	50586	*	CA C U3		35*
3	50	15	6	50591	*	NA BK		13
6	100	0	15	50592	*	PH S		75*

Figure 3.- OUTPUT. (This section lists all the possibilities which fit the input parameters. All intensities are I₃ values.)

3	75	25	3	50667	*	CU2 J		11
2	75	25	3	50702	*	KE		16
3	54	6	15	50724	*	GA2 SLJ		12
3	54	25	3	60324	*	(PR U1 .83) 11 .	32F	24
3	75	6	15	60344	*	CC CL		44
3	50	15	6	60347	*	Y U F		14
15	46	25	3	60366	*	BA2 SI U4		12
6	33	25	3	60381	*	PHC LT DR2 . 5 HZ C		11
3	33	25	3	60395	*	(SN U)	4T	16
4	66	6	15	60399	*	BA ZR C3		17
5	55	15	6	60400	*	BA2 CA W C6		33
3	50	25	3	60640	*	(MG D2)	3H	6
3	62	15	6	60644	*	(PC B)	8Q	17
3	55	25	3	70205	*	TL2 SI F6		12
3	54	15	6	70241	*	NA CA CD Y F8		5
7	58	15	6	70271	*	NA N U3		17
3	37	3	25	70279	*	MG2 (U H) CL U3 . 3 HZ O		13
5	55	15	6	80200	*	(MC5 CR6 FE18)	588	11
5	62	25	3	80376	*	PU U2		21
4	57	25	3	80383	*	(LI MG ZN)	24C	13
6	50	15	6	80455	*	BA MG C4		27
4	34	25	3	80457	*	BA W U4		18
5	45	25	3	80468	*	HG2 DR2		7
4	40	25	3	80474	*	NA I O3		11
3	75	6	6	80487	*	(SN TE)	8F	24
6	33	15	6	80497	*	GA P U4		5
3	54	15	6	90012	*	(B H)	4H	13
6	100	0	15	90096	*	(BE5 PD)	24F	44
6	40	15	6	90104	*	(CS2 C)	4F	15
6	100	0	10	90313	*	(BE5 PT)	24F	37
6	42	25	3	90447	*	B12 TE2 S		3
10	41	25	3	90477	*	AL AG TE4		11
5	55	25	3	100111	*	K3 CR F6		23
3	35	25	3	100225	*	(II SI2)	12Q	4
5	35	15	6	100423	*	AL P U4		5
8	68	15	6	100434	*	ZN S		32*
5	71	10	10	110213	*	BA B6		18
6	44	15	6	110345	*	CA (MN, MG) (C C3) 2		5
8	74	15	6	110513	*	(ZN .43 MNO .31 FEU .26) S		28
3	50	25	3	110608	*	GD2 O3		15
14	33	25	3	110641	*	(AC P O3) 4		18
4	34	25	3	110690	*	SB2 C5		21
6	100	0	10	120042	*	K2 L F6		18
11	36	25	3	120300	*	K2 CR2 O7		15
3	41	25	3	120338	*	BA MG GE2 C6		22

Figure 3.- Concluded.

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***** REPORT *****

THE FOLLOWING REPORT IS BASED ON THE RECVE TABLE AND CHEMICAL INFORMATION (BOTH POSITIVE AND NEGATIVE).

IF NO CHEMICAL INFORMATION WAS GIVEN AS INFLT, THE 10 PATTERNS THAT FOLLOW HAVE THE HIGHEST RELIABILITY FACTOR

THE ASTP NUMBER AND THE RELIABILITY PRECEED THE CHEMICAL FORMULA

THE TRUE RESULTS COULD BE A MIXTURE OF THE FOLLOWING POSSIBILITIES

THE 10 POSSIBILITIES WITH THE HIGHEST RELIABILITY FACTORS WILL BE LISTED IN MATCHC IN ORDER OF DECREASING RELIABILITY FACTOR

THE PRECONCEIVED POSSIBILITIES HAVE A RELIABILITY FACTOR OF 999

40804		50450		50452		50565		50566	
42		43		29		13		35	
LA Fz		SI OZ		ZN S		SI		ZN S	
1.932	100- 63	3.235	100- 62	3.306	100- 63	3.140	100- 63	3.120	100- 63
3.150	100- 63	4.264	39- 25	3.130	100- 63	1.921	63- 39	1.910	63- 39
1.646	39- 25	1.617	25- 15	2.928	100- 63	1.638	39- 25	1.632	39- 25
1.115	25- 15	1.542	15- 10	1.910	100- 63	1.108	25- 15	2.706	10- 6
1.365	15- 10	2.281	15- 10	1.765	63- 39	1.246	15- 10	1.103	10- 6
1.252	10- 6	2.460	15- 10	1.630	63- 39	0.918	15- 10	1.240	10- 6
0.604	10- 6	1.375	15- 10	2.275	39- 25	0.859	10- 6	1.350	6- 3
0.423	10- 6	1.372	10- 6	1.296	15- 10	1.045	10- 6	0.914	6- 3
1.021	10- 6	2.130	10- 6	1.102	15- 10	1.358	10- 6	1.040	6- 3
0.566	6- 3	1.382	10- 6	1.559	15- 10	0.828	6- 3	0.855	3- 2
0.622	3- 2	1.671	10- 6	1.210	10- 6	0.960	6- 3	0.956	3- 2
0.910	1- 0	1.978	6- 3	1.654	10- 6			0.824	2- 1
		2.225	6- 3	0.840	10- 6			1.208	2- 1
		1.200	6- 3	0.885	10- 6			1.501	2- 1
		1.082	6- 3	1.181	10- 6				
		1.160	6- 3	0.915	10- 6				
		1.184	6- 3	0.555	6- 3				
		1.255	6- 3	0.998	6- 3				
		1.268	3- 2	1.072	6- 3				
		1.452	3- 2	1.251	6- 3				

Figure 4.- REPORT. (This section lists d-spacings and intensities (I_3 based on the I_1 scale) for all the possibilities which match the chemical information. If no chemical information is used, then the 10 with the highest reliability factors are printed. The asterisk and/or number to the right of the formula denotes data quality and subfile.)

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1.044	6- 3	1.004	6- 3	4.415	6- 3	1.775	6- 3
1.515	6- 3	0.895	6- 3	1.432	6- 3	1.903	6- 3
1.625	6- 3	C.535	6- 3	1.566	6- 3	2.245	6- 3
C.577	3- 2	0.823	3- 2	1.787	6- 3	3.063	6- 3
1.C46	3- 2	C.831	3- 2	1.871	6- 3	1.951	6- 3
1.154	3- 2	1.C45	3- 2	2.181	6- 3	5.831	6- 3
1.180	3- 2	C.905	2- 1	2.442	6- 3	2.195	2- 1
1.421	3- 2	C.857	1- C	2.998	6- 3		
1.509	3- 2			6.645	6- 3		
2.645	3- 2			1.549	2- 1		
0.566	2- 1			1.679	2- 1		
1.C12	2- 1			1.708	2- 1		
1.C36	2- 1			1.896	2- 1		
1.235	2- 1			1.932	2- 1		
1.256	2- 1			2.C55	2- 1		
1.340	2- 1			2.601	2- 1		
1.474	2- 1						
1.566	2- 1						
C.576	1- C						
C.585	1- 0						
C.590	1- C						
1.023	1- C						
1.C61	1- 0						
1.124	1- C						
1.142	1- C						
1.248	1- 0						
1.265	1- C						
1.256	1- C						

Figure 4.- Concluded.

***** SUBST1 *****

THE FOLLOWING RESULTS REPRESENT AN ATTEMPT TO SUBTRACT STANDARD PHASES BASED ON INTENSITIES

THE PRECONCEIVED POSSIBILITIES WILL BE SUBTRACTED FIRST IN THE ORDER GIVEN AS INPUT

THE PRECONCEIVED POSSIBILITIES HAVE A RELIABILITY FACTOR OF 555

THE STANDARD PATTERNS WILL BE SUBTRACTED FROM THE UNKNOWN PATTERN IN ORDER OF DECREASING RELIABILITY FACTOR

(OBS)	(IGS)	(OBS)	(IGS LOG SCALE)
4.2700	14	4.2700	15- 10
3.8000	6	3.8000	6- 3
3.4300	61	3.4300	63- 39
3.3500	77	3.3500	100- 63
3.3200	26	3.3200	39- 25
3.1500	28	3.1500	39- 25
3.1340	34	3.1340	39- 25
3.0390	100	3.0390	100- 63
2.9730	77	2.9730	100- 63
2.9310	22	2.9310	25- 15
2.4550	5	2.4550	6- 3
2.4600	5	2.4600	6- 3
2.2670	12	2.2670	15- 10
2.2340	3	2.2340	3- 2
2.1300	8	2.1300	10- 6
2.1010	45	2.1010	63- 35
1.9418	3	1.9418	3- 2
1.9325	21	1.9325	25- 15
1.9141	32	1.9141	39- 25
1.8777	11	1.8777	15- 10
1.8203	9	1.8203	10- 6
1.7519	25	1.7519	25- 15
1.7674	5	1.7674	10- 5
1.7151	13	1.7151	15- 10
1.6734	4	1.6734	6- 3
1.6524	6	1.6524	6- 3
1.6328	23	1.6328	25- 15
1.5415	6	1.5415	10- 6
1.4660	5	1.4660	6- 3

BACKGROUND RADIATION VALUE IS 2 -- SCALED INTENSITIES OF STANDARD LESS THAN THIS SHOULD NOT BE OF CONCERN

Figure 6.- SUBST1. (I_3 values for the unknown pattern are converted to the log scale.)

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				RESULTING RESIDUE PATTERN			
I(OBS)	I(PI)	I(LI)	I(OBS)	I(STANDARD)	I(STANDARD)	I(OBS)	I(OBS)
4.2700	4.3011	4.2203	15			4.2700	15
3.6600	3.6635	3.6241	6	3.431	80	3.6600	6
3.4300	3.4542	3.4072	63			3.4300	-17
3.3500	3.3727	3.3278	100			3.3500	100
3.3200	3.3389	3.2949	39			3.3200	39
3.1500	3.1656	3.1255	35			3.1500	39
3.1300	3.1496	3.1104	39			3.1300	39
3.0350	3.0534	3.0166	100			3.0350	100
2.9730	2.9899	2.9542	100	2.572	80	2.9730	19
2.9310	2.9455	2.9112	25			2.9310	25
2.4990	2.5054	2.4845	6			2.4990	6
2.4600	2.4722	2.4480	6			2.4600	6
2.2670	2.2562	2.2753	15			2.2670	15
2.2340	2.2447	2.2247	3			2.2340	3
2.1300	2.1350	2.1209	10			2.1300	10
2.1010	2.1119	2.0542	63	2.099	50	2.1010	12
1.9418	1.9512	1.9361	3			1.9418	3
1.9325	1.9399	1.9249	25			1.9325	25
1.9141	1.9212	1.9006	39			1.9141	39
1.8777	1.8850	1.8705	15			1.8777	15
1.8203	1.8265	1.8132	10			1.8203	10
1.7919	1.7969	1.7841	25	1.791	31	1.7919	-5
1.7674	1.7746	1.7621	10			1.7674	10
1.7151	1.7157	1.7079	15	1.714	20	1.7151	-4
1.6734	1.6793	1.6661	6			1.6734	6
1.6524	1.6570	1.6461	6			1.6524	6
1.6326	1.6380	1.6273	25			1.6326	25
1.5419	1.5468	1.5373	10			1.5419	10
1.4860	1.4914	1.4826	6	1.485	8	1.4860	-1

THE STANDARD WITH ASTM NUMBER 50552 HAS A SCALING FACTOR OF 0.007 AND A FORMULAE OF PB 5

Figure 7.- SUBSTI. (Intensities for the standard with the highest reliability are scaled down and subtracted from the unknown pattern. The next standard will be scaled down to the residue pattern.)

D(CBS)	I(I)	G(II)	I(CBS)	D(STANDARD)	I(STANDARD)	RESULTING RESIDUE PATTERN D(CBS)	I(CBS)
4.2700	4.3011	4.2283	15	4.264	27	4.2700	-11
3.8600	3.8835	3.8241	6			3.8600	6
3.4300	3.4542	3.4072	-17			3.4300	-17
3.3500	3.3727	3.3278	100	3.339	70	3.3500	30
3.3200	3.3389	3.2949	39			3.3200	39
3.1500	3.1656	3.1259	39			3.1500	39
3.1340	3.1490	3.1104	25			3.1340	39
3.0350	3.0534	3.0166	100			3.0390	100
2.9730	2.9855	2.9542	15			2.9730	19
2.9310	2.9455	2.9112	25			2.9310	25
2.4950	2.5054	2.4845	0	2.460	10	2.4950	6
2.4600	2.4722	2.4480	6			2.4600	-4
2.2870	2.2982	2.2753	15	2.281	10	2.2870	4
				2.235	4		
2.2340	2.2447	2.2247	3			2.2340	0
2.1300	2.1390	2.1269	10	2.130	7	2.1300	3
2.1010	2.1115	2.0942	12	1.978	4	2.1010	12
1.9410	1.9512	1.9361	3			1.9410	3
1.9325	1.9395	1.9249	25			1.9325	25
1.9141	1.9212	1.9006	39			1.9141	39
1.8777	1.8850	1.8709	15			1.8777	15
1.8203	1.8265	1.8132	10	1.817	17	1.8203	-7
				1.800	0		
1.7919	1.7969	1.7841	-5			1.7919	-5
1.7674	1.7740	1.7621	10			1.7674	10
1.7151	1.7157	1.7075	-4			1.7151	-4
1.6734	1.6793	1.6681	6	1.671	7	1.6734	0
				1.660	2		
1.6524	1.6570	1.6461	6			1.6524	6
1.6328	1.6380	1.6273	25	1.609	0	1.6328	25
				1.542	10		
1.5419	1.5468	1.5373	10			1.5419	0
1.4860	1.4914	1.4826	-1	1.452	2	1.4860	-1

THE STANDARD WITH ASTM NUMBER 50450 HAS A SCALING FACTOR OF 0.703 AND A FORMULAE OF SI 02

Figure 7.- Concluded.

3.3500	100	3.3727	3.3278	3.356					2	30
3.3200	25	3.3385	3.2545	3.339	70					10
				3.306				1		0
				3.306						0
				3.306			9		16	0
				3.295						0
				3.252						0
3.1500	25	3.1656	3.1255	3.150	24					10
				3.140					0	
3.1340	25	3.1456	3.1164	3.130				1		-12
				3.130			5			
				3.120		48			1	
				3.101						0
				3.063					2	
				3.044						43
3.0390	100	3.0534	3.0166	3.035		54			1	
				2.958						19
2.9730	100	2.9895	2.9542	2.972	80					5
2.9310	25	2.9455	2.9112	2.928				1		
				2.928				9		9
				2.928						
				2.911						
				2.845			1			
				2.706		4				3
				2.677						
				2.601					0	
				2.541						0
2.4990	6	2.5044	2.4645	2.457		6				-2
				2.451					1	
				2.440					1	
				2.460						
2.4000	8	2.4122	2.4480	2.442	10					-4
2.2800	15	2.2962	2.2753	2.286		13			1	-13
				2.281	10					
				2.275			5			
				2.255					0	

Figure 8.- Continued.

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				2.245					0	
				2.235	4					0
2.2340	3	2.2447	2.2247	2.195					0	
				2.181				1		3
2.1300	10	2.1390	2.1205	2.130	7					-1
2.1010	23	2.1115	2.0542	2.055				0		
				2.049	50					2
				2.055						0
				2.054			13			0
				2.014						0
				1.978	4					0
				1.951						2
1.9418	3	1.9512	1.9361	1.922						-4
1.9325	25	1.9399	1.9249	1.922	29			0		
				1.929						
				1.921					0	
1.9141	34	1.9212	1.9006	1.914						-11
				1.910		30				
				1.910						
				1.910						
				1.903						
				1.896						
1.8777	15	1.8850	1.8709	1.874						0
				1.871						
				1.857						
1.8202	10	1.8223	1.8122	1.817	17					-7
				1.800	0					
1.7949	25	1.7969	1.7841	1.791	31					-5
				1.787						
				1.775				1		2
1.7614	10	1.7746	1.7621	1.765						
				1.765						
				1.752						
1.7151	15	1.7157	1.7075	1.714	20				1	-3

Figure 8.- Continued.

				1.70e					0	
				1.675					0	
1.6736	0	1.6793	1.6681	1.671	7					0
				1.666	2					
				1.654			1		C	
				1.654						
1.6524	0	1.6570	1.6461	1.646		11				-2
				1.636						
				1.635					1	G
1.6320	2>	1.6380	1.6273	1.633		1d				0
				1.620				5		
				1.620					C	
				1.625			3			
				1.605	0					
				1.604			5			
				1.555				2		
				1.555					0	
				1.549					0	
				1.566			1			
				1.566					1	
				1.564					C	
				1.561						
				1.542			0			
1.541	10	1.5488	1.5373	1.542	10					0
				1.520				3		
				1.519				3		
				1.509				1		
1.4860	0	1.4914	1.4826	1.485						-1
				1.474						
				1.463					0	
				1.452						
				1.452	2				4	

IF THE ABOVE RESULTS DO NOT RESULT IN "AN IDENTIFICATION", IT IS SUGGESTED THAT THE PARAMETERS BE CHANGED AND THIS PHASE REPEATED
 THE EXECUTE TIME FOR THIS RUN WAS 2632 HUNDRETHS OF SECONDS (CPU TIME)
 THE EXECUTE TIME FOR THIS RUN INCLUDING ALL I/O WAS 3098 HUNDRETHS OF SECOND

Figure 8.- Concluded.

matches, intensity agreement, and spacing agreement. Experience has shown that a reliability factor greater than 33 and a log intensity match greater than 25 indicate a strong probability of the presence of that phase. If the input parameters are too restrictive (e.g., error window of 2 and log intensity match of 4 when the pattern has only 6 to 8 lines) and no possibilities match the input data, then an error message will be printed in this section. It can be identified by the statement "ABEND CODE IS: SYSTEM OOC5."

(3) *REPORT*- The entire pattern for those compounds which are chemically correct is given (fig. 4). If no chemical information is provided, then the 10 compounds with the highest reliability factors will be printed. Each compound listed is headed by its ASTM number, reliability factor, formula, and to the right is a number denoting its subfile, as follows:

blank = An inorganic pattern
2 = Organic
3 = Dual
4 = Inorganic, mineral
5 = Greater than 10Å (organic)
6 = Organic, mineral
7 = Greater than 10Å (inorganic)
8 = Cross-indexed minerals
9 = Greater than 10Å (dual)

If chemical information is used as input but no chemical formula occurs on the ASTM card, then the compound will not be listed in *REPORT*, *MATCHD*, or *SUBSTI*. Thus, the *OUTPUT* section should be visually scanned for possibilities with high reliability factors and intensity matches, but without chemical formulae.

(4) *MATCHD*- The 10 best matches are listed in order of decreasing reliability (fig. 5). The numbers and asterisk to the right denote the subfile and data quality. Below this to the left, the unknown pattern, with intensities and error windows, is listed. The next column lists the d-spacings of the 10 best matches which are then listed to the right. Each possibility is headed by its ASTM number and reliability factor. Under the heading are the I_3 intensities (grouped according to the I_1 scale) which correspond to the standard d-spacings to their left.

(5) *SUBSTI*- This section attempts to subtract standard phases from the unknown pattern, one at a time, based on intensities. This results in a final residual pattern. Intensities of the unknown are converted to the same log scale as the standards (figs. 6 and 7) before execution. *SUBSTI FINAL REPORT* (fig. 8) lists d-spacings and scaled intensities of all the standard together.

A scaling factor is used to scale down the intensities of the standards to those of the unknown. This is calculated as

$$\text{Scaling factor} = \frac{\sum I_{\text{unknown}}}{\sum I_{\text{standard}}}$$

where I_{unknown} are the intensities of the unknown pattern whose d-spacings match those of the standard to which it is compared. These values may be negative if already subtracted by a previous standard with a higher degree of confidence. It is here that a preconceived possibility is useful. A known phase will be subtracted first, scaling down any later possible phases to insignificance if their identification relied on lines belonging to the known phase. SUBSTI FINAL REPORT has the same format as MATCHD, except that now scaling factors have been calculated, standard intensities have been scaled down, and each standard has been subtracted from the unknown pattern.

III. PROGRAM INPUTS AND OPERATION

The Johnson-Vand program is simple to operate. A minimum of 8 data cards (described below) are placed inside a deck of 15 job cards. The data follow the first 14 job cards and the final job card is placed at the back of the deck. The deck is then given a job header card (see fig. 9). Table 3 describes the data card formats.

TABLE 3.- DATA CARD FORMATS

DATA CARD 1	This card may contain any information (not beyond column 76) to <i>identify</i> the run.
DATA CARD 2	The parameter card. The program will supply a reasonable set of parameters, default parameters if a value of zero or blank is given. The parameters are:
Col. 1(A)	<p><i>IFL</i>, the subfile of the ASTM powder diffraction file to be searched. Set <i>IFL</i> as follows:</p> <p style="margin-left: 40px;">blank = all subfiles A = alloy O = organic I = inorganic D = dual (e.g., both inorganic and organic) default = blank (entire file) M = mineral</p>
Col. 3(I)	<p><i>RESOL</i>, resolution condition</p> <p style="margin-left: 40px;">0 = normal 1 = Guinier default = 0</p>
Col. 5-8(I)	<p><i>MM</i>, the number of lines in unknown pattern</p> <p style="margin-left: 40px;">default = computer will count number of peaks</p>

TABLE 3.- Continued.

Col. 9-12(I)	<i>IW</i> , the error window default = 2
Col. 13-16(I)	<i>KUTØFF</i> , the minimum acceptable value of log intensity match default = 2
Col. 17-20(I)	<i>NUMBER</i> , the minimum acceptable number of line matches default = 3
Col. 25-28(I)	<i>IPERCT</i> , the minimum acceptable number of line matches default = 33
Col. 29-32(I)	<i>ICYCLE</i> , the number of cycles default = 0
Col. 33-36(I)	<i>IWCY</i> , the increase of <i>IW</i> per cycle default = +1
Col. 37-40(I)	<i>KUTOCY</i> , the increase of <i>KUTØFF</i> per cycle default = +5
Col. 41-44(I)	<i>NUMCY</i> , the increase of <i>NUMBER</i> per cycle default = +1
Col. 45-48(I)	<i>IPERCY</i> , the increase of <i>IPERCT</i> per cycle default = +10
Col. 49-52(I)	<i>JBKGR</i> , the background intensity (0 to 100 scale) default = +1 or half lowest given intensity
Col. 53-60(F)	<i>DHI</i> , the upper limit of the d-spacing range observed in the diffraction pattern default = error window above largest measured d
Col. 61-68(F)	<i>DLO</i> , the lower limit of the d-spacing range observed default = error window below smallest measured d

TABLE 3.- Continued.

Col. 69-73(A)	OPTION
	<p>SOLID = Solid solution MINOR = Minor phase MAJOR = Major component</p> <p>default = Major</p>
DATA CARD 3	<p>The positive element and preconceived possibilities card.</p> <p><i>Chemical elements</i> on this card and on Card 4 must be right justified, two columns per element; that is, single letter elements must be punched with a blank, then the letter: for example, a list of sodium, hydrogen, lithium, iron, nickel, oxygen, and platinum would be punched</p> <p>NA HLIFENI OPT</p> <p>With the first N in column 1 and none beyond column 50. RE (Rare Earth) punched in columns 49 and 50 will cause all the rare earth elements from La to Lu, inclusive, to be used as positive elements, in addition to any others punched in columns 1 through 48. The letters TU (transuranium) punched in columns 49 and 50 of the position element card will cause all the elements from Ac to Fm to be included automatically in the positive element list. A Q in column 1 calls for the periodic table.</p> <p><i>Preconceived possibilities-</i> The ASTM card numbers patterns which are to be printed out even though not found by the search program. Each must consist of six digits with no spaces. (A maximum of five patterns can be listed as preconceived possibilities. As an example, if patterns 1-24, 6-432, 11-4, 12-100, and 16-432, were known to be present, then the card would contain 010024060432110004120100160432 (starting in column 51). In other words, the six numbers are divided into a two-digit field for the card set and a four-digit field for the card in that set. The minimum contents for this card is 000000.)</p>
DATA CARD 4	<p>The negative element card. These must be punched right justified, two columns per element as in Card 3 with none beyond column 80. A Q punched in column 1 will cause all elements (through Fermium) not specifically designated as positive elements to be used as negative elements.</p>
DATA CARD 5	<p>Positive Functional Groups. Those functional groups which are known to be <i>present</i> in the unknown (from spot or other chemical tests).</p>

TABLE 3.- Concluded.

DATA CARD 6	Negative Functional Groups. Those functional groups which are known to be <i>absent</i> in the unknown (from spot or other chemical tests).
	NOTE: The input for both these cards are as follows: Punch chemical group exactly as the group appears in figure 3 (**OUTPUT**) under FORMULA. Notice the spaces - this is extremely important. Eight groups can be external, starting in columns 1, 11, 21, etc.
DATA CARD 7 thru N	These cards contain the pairs of d-spacings and intensities measured on the unknown pattern. These need not be in order. Punch the d-spacing, then its intensity (scale 1-100). The d-spacing <i>must</i> contain a decimal point and the intensity <i>must not</i> contain a decimal point. These cards are of the format (8(F7.3,I3)). <i>Then one blank card.</i> Cards 1-N may be repeated as many times as unknown diffraction patterns are available.

A printout can be obtained with only a data set of spacings and intensities (Card 7-N) along with 7 blank cards in the proper places. The program provides a reasonable set of parameters (by default) if none are input.

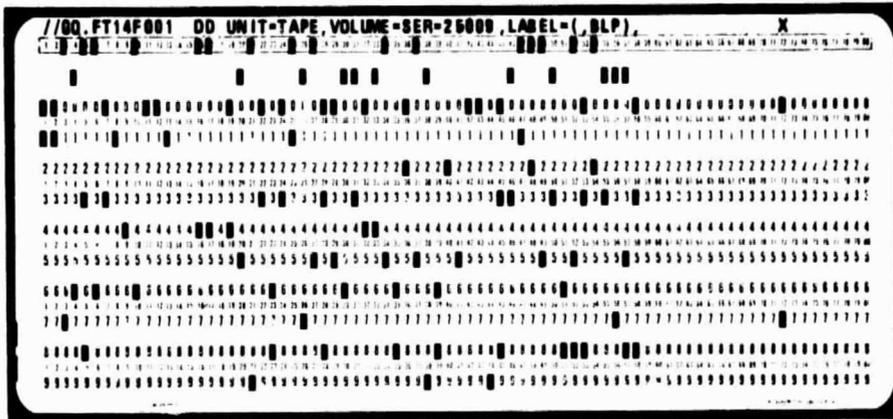
On Card 2, all numerical parameters should be right justified in their fields. For example, an error window (IW) of 3 which has a field of columns 9-12 should be punched into column 12. Remember that a zero on this card is read as a blank and a default parameter will be used. It is impossible to give a parameter a value of zero.

On Cards 7-N, the diffraction data cards, the format is (8(F7.3,I3)). That is, for each card which has 80 columns, there are 8 fields of 10 columns each for paired spacings and intensities. Each of these 10 column fields is divided into a 7- and a 3-column field for the spacing and intensity, respectively. In the 7-column field, if no decimal is used, all blanks are counted as zeros and a decimal is placed automatically before the three right-hand digits. If a decimal is used, the spacing value may be placed anywhere within this field. The 3-column intensity field *must* be occupied by an integer which *must* be right justified. All blanks in this field are read as zeros. At least one of the intensities *must* equal 100.

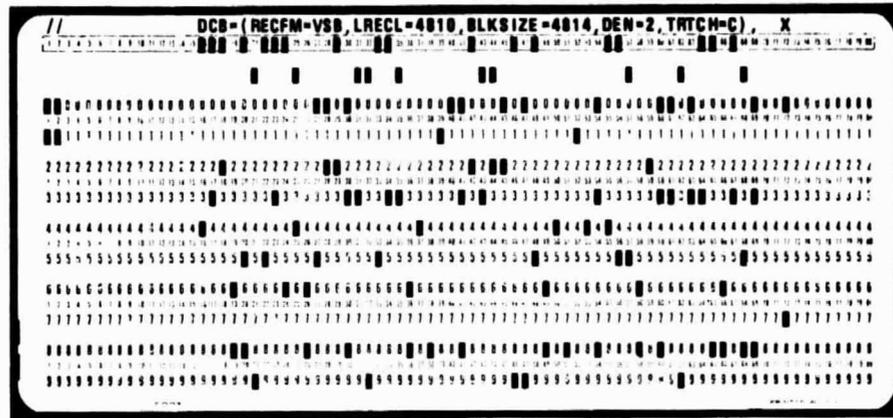
All data cards 1-N must be followed by a blank card to end the search.

A typical run would probably use the mineral subfile. The error window would be defaulted to 2, or set at 3. All other parameters would probably be defaulted except perhaps the log intensity match, which might be set at 4 (or

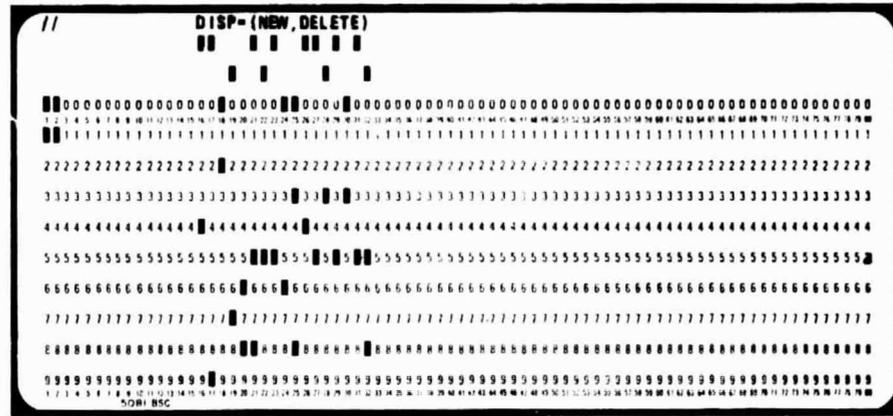
No. 9
JOB CARD-8



No. 10
JOB CARD-9



No. 11
JOB CARD-10



No. 12
JOB CARD-11

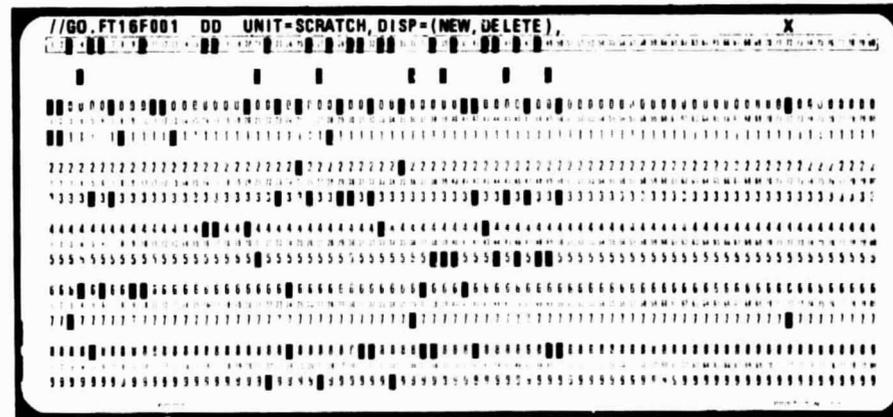
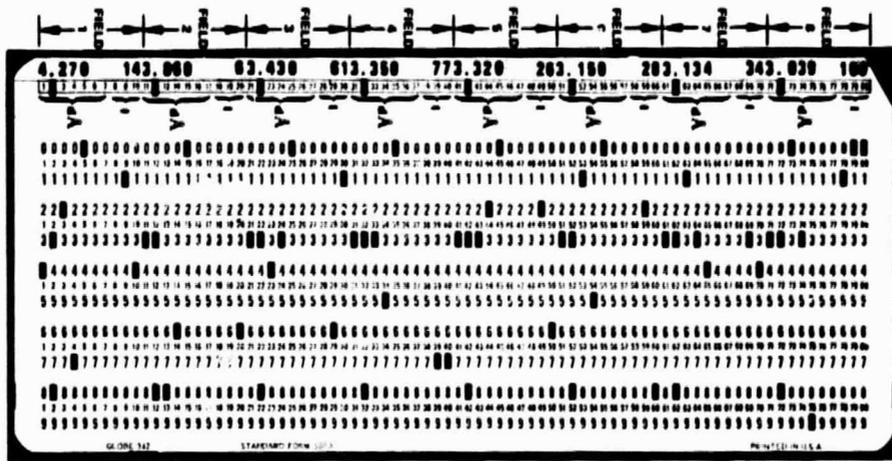
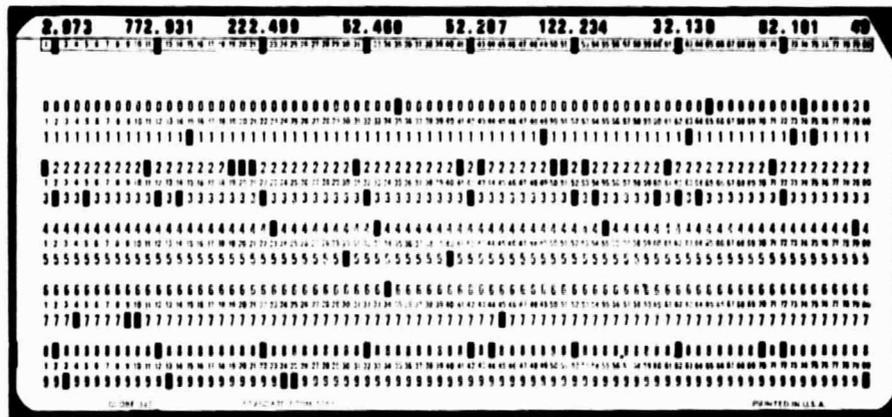


Figure 9.- Continued.

No. 22
DATA CARD (4 SPACINGS &
INTERSTITIES)-7



No. 23
DATA CARD (4 SPACINGS &
INTERSTITIES)-8



No. 24
DATA CARD (4 SPACINGS &
INTERSTITIES)-9

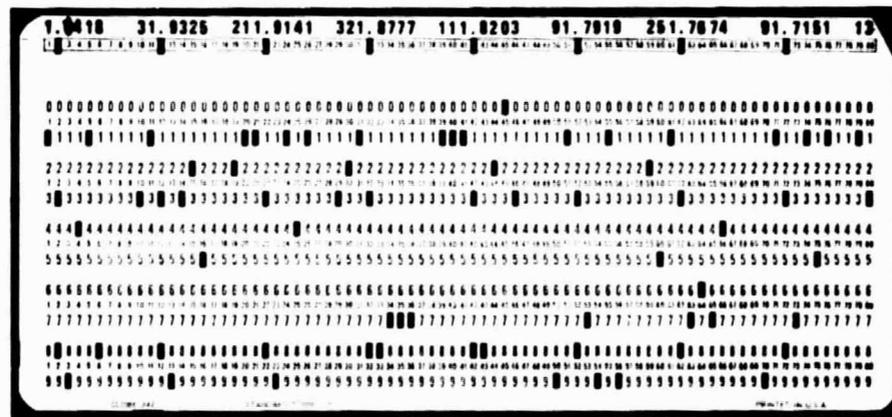


Figure 9.- Continued.

7 for a good diffractometer scan). If an identification did not result, data should be rechecked and the error window should be expanded and other parameters increased by small amounts to limit the amount of output. With experience, an operator should get a feel for what the capabilities of the system are.

IV. A WORKED EXAMPLE

A set of worked examples has been prepared. The reader is referred to Appendix I which is a package of computer printouts. This package is available on loan from Max Blanchard at Ames Research Center or Dr. Marshall E. Maddock at San Jose State University. Appendix I comprises nine printouts obtained from Johnson and Vand's example (figs. 2-8) and from two mixtures of minerals (Tables 1 and 2) which were X-rayed with the Debye-Scherrer powder cameras (57.3- and 114.7-mm diameters) and the X-ray diffractometer (at different scan speeds).

A. Sample Number 5 (CaF_2 , SiO_2 , ZnS , CaCO_3 , PbS)

This is the entire output of the Johnson and Vand example. The entire inorganic file was searched. Chemical information was used. The only input parameters were the range of observed d-spacings. The effect of using chemical information can easily be appreciated here as it reduced a total of 170 possibilities to only 11. From there, it easily identified the five phases present.

B. ASTM 2, 2A, 5, and 4F

These four printouts were obtained from a mixture of approximately equal amounts of PbS , CaF_2 , TiO_2 , $(\text{Mg,Fe})_2\text{SiO}_4$, and $\text{Fe}(\text{Cr,Al})_2\text{O}_4$. Unlike the Johnson and Vand example, two minerals in this mixture are subject to considerable solid solution and standard patterns in the Powder Diffraction File, for these minerals represent only points along a solid-solution sequence. Thus, standard intensities and d-spacings could vary significantly from those observed in an unknown sample.

Data for ASTM 2 were obtained from a large Debye-Scherrer powder camera. All of the parameters were defaulted and the mineral subfile was searched. CaF_2 and PbS were easily identified in OUTPUT with high reliabilities and intensity matches. TiO_2 had the next highest reliability but a low-intensity match. $(\text{Mg,Fe})_2\text{SiO}_4$ and $\text{Fe}(\text{Cr,Al})_2\text{O}_4$ were not identified because their strong lines at 2.27\AA and 2.068\AA , respectively, were not measured. Inspection of the X-ray film confirmed their existence but their intensities were very weak and spotty. The data were not good enough to identify these phases. In SUBSTITUTIONAL FINAL REPORT, cordierite and montmorillonite were listed as good possibilities, as well as the other three phases. Here, chemical information would have been helpful in determining the actual phases present. The program was, however,

successful, using default parameters, in searching the approximately 2000 mineral subfile and listed five good possibilities without the use of chemical information. Three of these five were correct.

Data for ASTM 2A were obtained from a short exposure on a small Debye-Scherrer camera. All the parameters were defaulted and the mineral subfile was searched. None of the possibilities listed had confidence levels high enough to be considered as an identification. It is assumed that the exposure time was too short to darken the film and that too few diffraction lines were measured for an identification. Thus another, longer, exposure was taken and named ASTM 5.

Output for ASTM 5 was from data for 28 lines, whereas ASTM 2A had only 17 lines for the same range of d-spacings. The data were run at an error window of ± 3 , and only the mineral subfile was searched. Results were comparable to those on the large camera. TiO_2 , PbS, and CaF_2 were easily identified, but the two components with solid solution were missed again. Attempts at broadening the error window were futile because too many possibilities were selected. In general, a broad window of ± 4 is suitable only for data with chemical information.

Data for printout ASTM 4F was obtained from a slow diffractometer scan at $1/4^\circ 2\theta/\text{min}$. This was much more successful than with the powder cameras. This is attributed to the diffractometer's ability to resolve weak lines and the greater accuracy of line location and peak height which are inherently better on diffraction charts. These data were processed with default parameters and only the mineral subfile was searched. Without chemical information only 20 possibilities were listed in OUTPUT. Six of the 20 represented the 5 known mineral phases and 2 others (spinel) were isostructural with the chromite. SUBSTI FINAL REPORT lists all except olivine as having a high probability, and the only incorrect phase listed there is BeO, an unlikely component.

Observation of the log-intensity matches listed led to the conclusion that the output could be improved if this parameter were increased. Another computer run was made with a log-intensity match of 4. This is ASTM 4FA. A brief glance at OUTPUT and SUBSTI FINAL REPORT indicates an excellent match of all phases except olivine, with the only other phases listed being BeO and NiFe_2O_4 , again, a spinel isostructural with chromite.

C. BSTM 1 and 2

Another mixture, this time composed of equal weights of rutile (TiO_2), galena (PbS), zircon (ZrSiO_4), Fluorite (CaF_2), and calcite (CaCO_3) was prepared. Of these, only the calcite exhibits solid solution with the replacement of Ca by Mg, and it was a relatively Ca-pure sample. Two diffractometer scans were run at $1/4^\circ 2\theta/\text{min}$ and at $1^\circ 2\theta/\text{min}$ and labeled BSTM 1 and BSTM 2, respectively.

Both data sets were recorded in two ways. One was to read directly off the diffraction charts (BSTM 1 and 2) and the other (BSTM 1A and 2A) was to

subtract $0.05^\circ \theta$ to compensate for misalignment of the goniometer. (Note: $0.05^\circ \theta$ is equivalent to about $1d^*$.) These four data sets were then input with default parameters except for log-intensity match at 4 and DHI at 8.845\AA corresponding to an angle of $10^\circ 2\theta$. Background radiation was read directly off the charts and only the mineral subfile was searched.

BSTM 1 at $1/4^\circ 2\theta/\text{min}$ had an output of only 10 possibilities uncorrected and 13 when corrected by $0.05^\circ \theta$. In both cases, all five known phases were identified. The corrected output had higher reliability factors in every case except zircon, which matched with 11 lines instead of 12 after being corrected.

In both cases, SUBSTI FINAL REPORT listed the five known phases as the only ones with scaling factors above 0.1, the lowest of these being calcite at 0.206. The remaining possibilities had been scaled down so low because their identifications had been dependent on lines generated by those phases with higher reliabilities. When it came time to calculate a scaling factor for these incorrect phases, there was little or no pattern left for them to compare to.

BSTM 2 at $1^\circ 2\theta/\text{min}$ uncorrected had an output of eight possibilities, correctly identifying every phase except calcite. The corrected data set listed only 10 possibilities, including calcite, and reliability factors for the known phases were greatly enhanced. Once again, in both cases, the known phases were the only ones listed with scaling factors greater than 0.1 and a low factor for calcite at 0.189. Some very successful runs indeed!

IV. SUMMARY AND SUGGESTIONS

It has been demonstrated that this program can easily identify mixtures of minerals which can be quite difficult to resolve manually. There is still some difficulty in identifying phases which are subject to solid solution, it is hoped that when the master file is updated from Set 19 to Set 24 this will be less of a problem. The update will nearly double the data file and this should be accomplished in the near future. When a number of spacings have not been identified, solid solution should be suspected. The best way to resolve this would be to use chemical information, a wider error window (perhaps ± 4), and the OPTION parameter. Remember, though, that it is possible that a phase is not identified because its pattern is not in the master file.

When inputting data, default parameters should be sufficient in most cases. An error window of ± 3 might be needed when there is a poor resolution of lines. With confidence in intensity measurements a log-intensity match of 4 will greatly reduce the number of possibilities, requiring that standard intensities down to 26 must match with lines of the unknown pattern. A second cycle is usually not desirable!

Remember to input the entire range of d-spacings, especially DHI. When inputting intensities, keep in mind the log scale the program uses. Note that, in the worked examples, all intensities are input on this scale. Remember, at least one intensity *must* equal 100.

As an operator uses the program more often, he will become more familiar with its capabilities. He should always keep in mind, however, that the program merely lists possibilities with different degrees of confidence. The worked examples presented were quite successful; however, at other times incorrect identifications with high reliabilities have been observed. In the end, it is the responsibility of the operator, *not* the computer, to decide which phases are actually present.